EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	6	(memory near2 system) same (bit$1lin$2 near2 leakage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:05
L2	167	memory same (bit$1lin$2 near2 leakage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:05
L3	3	2 same (detect$3 near2 voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:06
L4	11	2 and (detect$3 near2 voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:06
L5	11	4 and current$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:07
L6	6	4 and (current$4 near5 (increment$3 or increas$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:08
L7	23540	(programming adj5 memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:08
L8	1750	L7 and incremental$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:08

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L9	36	L8 and (current adj3 bit$1lin$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:08
L10	19	(programm$3 adj3 memory adj5 cell$1) near10 ((incremental or incrementally or increment$3 or extent or increase) adj5 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:09
L11	4	2 and 10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:09
L12	4	2 and 9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:09
L14	0	(method and (bitline near2 leakage) and memory and (detect$3 near3 voltage) and bitline and array and amplitude and (leakage near2 curent$4) and increment$4).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:18
L18	1	(memory and array and bitline and (first near2 circuit) and equal and programm$3 and voltage and (second near2 voltage) and measure and (current$3 near2 source)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:21
L19	1	(memory and array and cell and bitline and (current$3 near2 source) and (first near2 current$3) and node and (second near2 current$3) and detect$3 and voltage and equal).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:23
L20	21	sarin-vishal.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:23

L21	3	tran-hieu.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:23
L22	59	lee-dana.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:24
L23	26	8 and 365/189.01,191.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:25
L24	2	9 and 365/189.01,191.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:25
L25	4	2 and 365/189.01,191.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:25
S1	344	(memory adj3 system) and (memory adj2 array) and (address adj3 interfac$2) and (control adj3 circuit)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 10:53
S2	28	S1 and decoder and (voltage adj3 generator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 10:53
S4	3	(memory adj2 array) and (address adj3 interfac$2) and (control adj3 circuit) and (I/O adj3 interface) and (voltage adj3 generator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 10:55
S5	32	(memory adj2 array) and (address adj3 interfac$2) and (control adj3 circuit) and (voltage adj3 generator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 10:55

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S6	18	S5 and "365"/$7.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 10:55
S12	19483	(programming adj5 memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 10:58
S13	1429	S12 and incremental$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 11:07
S14	27	S13 and (current adj3 bit$1lin$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:08
S15	27	S14 and select$2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 11:04
S16	6	(("5289411") or ("5572054") or ("6282145")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/16 11:06
S17	6	S12 same (incremental$3 adj5 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 11:11
S18	1	S12 same ((increment or incremental or incrementll$3) adj5 current$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 11:12

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S19	229	S12 and ((increment or incremental or incrementll$3) adj5 current$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 11:12
S21	44	S19 and "365"/$7.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 14:53
S22	730	(programm$3 adj3 memory adj5 cell$1) and ((incremental or incrementally or increment$2 or extent or increase) adj5 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 14:55
S23	14	(programm$3 adj3 memory adj5 cell$1) near10 ((incremental or incrementally or increment$2 or extent or increase) adj5 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:09
S24	396	S22 and (selected adj5 memory adj5 cell)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 14:59
S25	258	S24 and substantially	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:00
S26	152	S25 and leakage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:29
S27	4	S26 and 365/189.01.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:33

S28	131	S26 and "365"/$7.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:33
S29	108	S28 and detect$3 and voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:33
S30	108	S29 and circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:33
S31	80	S30 and (current adj3 source)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:39
S32	4	S28 and 365/189.01,189.02,230.01.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:42
S33	3	tran-hieu.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:42
S34	3	tran-hieu-.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:42
S35	21	tran-hieu-v.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:42

S36	93	tran-hieu-$.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:45
S37	9	sarin-vishal.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:43
S38	0	sarin-vishal-$.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:43
S39	35	lee-dana.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:43
S40	9	lee-dana-$.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:43
S41	0	(method and programm$3 and memory and cell and incremental and current and bit$1lin$2 and selected and leakage).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:10
S42	0	(bit$1line and leakage and memory and detect$3 and voltage and array and current and incremental).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 15:48
S43	0	(memory and array$1 and cell$1 and bit$1lin$2 and circuit and output and voltage and programm$3 and measure and current and source and detect$3). clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/12 09:10

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S44	1	(memory and array and cell and bit$1line and first and second and current and source and detector and input and output and voltage and equal and substantially).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 16:00